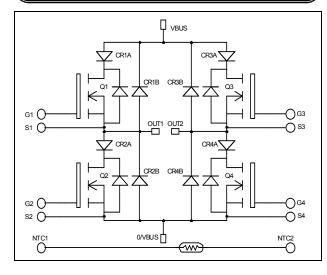
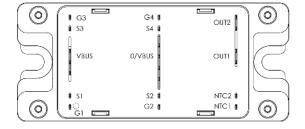


Full bridge Series & SiC parallel diodes MOSFET Power Module





$$\begin{split} V_{DSS} &= 500 V \\ R_{DSon} &= 75 m \Omega \text{ typ @ Tj} = 25^{\circ} C \\ I_D &= 46 A \text{ @ Tc} = 25^{\circ} C \end{split}$$

Application

- Motor control
- Switched Mode Power Supplies
- Uninterruptible Power Supplies

Features

- Power MOS 7® MOSFETs
 - Low R_{DSon}
 - Low input and Miller capacitance
 - Low gate charge
 - Avalanche energy rated

• Parallel SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin source for easy drive
- Very low stray inductance
- Lead frames for power connections
- Internal thermistor for temperature monitoring
- High level of integration

Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

All ratings @ $T_j = 25$ °C unless otherwise specified

Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Breakdown Voltage		500	V
т	(ontinuous I)rain (urrent	$T_c = 25^{\circ}C$	46	
I_{D}		$T_c = 80^{\circ}C$	34	A
I_{DM}	Pulsed Drain current		184	
V_{GS}	Gate - Source Voltage		±30	V
R _{DSon}	Drain - Source ON Resistance		90	mΩ
P_D	Maximum Power Dissipation	$T_c = 25$ °C	357	W
I_{AR}	Avalanche current (repetitive and non repetitive)		46	A
E_{AR}	Repetitive Avalanche Energy		50	T
E_{AS}	Single Pulse Avalanche Energy		2500	mJ

TAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



Electrical Characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 500V$ T	$T_j = 25^{\circ} C$			100	A
		$V_{GS} = 0V, V_{DS} = 400V$ T	$T_{\rm j} = 125^{\circ}{\rm C}$			500	μΑ
R _{DS(on)}	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 23A$			75	90	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 2.5 \text{mA}$		3		5	V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$				±100	nA

Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V$		5590		
C_{oss}	Output Capacitance	$V_{\rm DS} = 25V$		1180		pF
C_{rss}	Reverse Transfer Capacitance	f=1MHz		85		
Q_{g}	Total gate Charge	$V_{GS} = 10V$		123		
Q_{gs}	Gate – Source Charge	$V_{\text{Bus}} = 250V$		33		nC
Q_{gd}	Gate – Drain Charge	$I_D = 46A$		65		
$T_{d(on)}$	Turn-on Delay Time	Inductive switching @ 125°C		18		
$T_{\rm r}$	Rise Time	$V_{GS} = 15V$ $V_{Bus} = 333V$ $I_D = 46A$		35		
$T_{d(off)}$	Turn-off Delay Time			87		ns
T_{f}	Fall Time	$R_G = 5\Omega$		77		
Eon	Turn-on Switching Energy	Inductive switching @ 25°C		453		T
E_{off}	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 333V$ $I_D = 46A, R_G = 5\Omega$		726		μJ
Eon	Turn-on Switching Energy	Inductive switching @ 125°C $V_{GS} = 15V, V_{Bus} = 333V$ $I_D = 46A, R_G = 5\Omega$		745		
E _{off}	Turn-off Switching Energy			846		μJ
R_{thJC}	Junction to Case Thermal Resistance				0.35	°C/W

Series diode ratings and characteristics

Symbol	Characteristic Test Conditions		Min	Тур	Max	Unit	
V_{RRM}	Peak Repetitive Reverse Voltage					600	V
I_{RM}	Reverse Leakage Current	$V_{R} = 600V$				50	μΑ
I_{F}	DC Forward current		$Tc = 80^{\circ}C$		50		A
W	Die I. Ferrand Welter	$I_F = 50A$	$T_i = 25^{\circ}C$		1.6	2	V
V_{F}	Diode Forward Voltage	$V_{GE} = 0V$	$T_{i} = 150^{\circ}C$		1.5		V
+	Reverse Recovery Time	$I_F = 50A$ $V_R = 300V$ $di/dt = 1800A/us$	$T_j = 25$ °C		100		ns
t_{rr}	Reverse Recovery Time		$T_{j} = 150^{\circ}C$		150		115
0	Reverse Recovery Charge		$T_j = 25$ °C		2.6		μС
Q_{rr}	Reverse Recovery Charge		$T_{i} = 150^{\circ}C$		5.4		μС
Г	D D E		$T_i = 25^{\circ}C$		0.60		_
E_{rr}	Reverse Recovery Energy		$T_{\rm j} = 150^{\circ}{\rm C}$		1.2		mJ
R_{thJC}	Junction to Case Thermal Resistance					1.42	°C/W



Parallel diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Peak Repetitive Reverse Voltage					600	V
I_{RM}	Reverse Leakage Current	age Current V _R =600V	$T_j = 25^{\circ}C$		100	400	μA
I_{F}	DC Forward Current		$T_j = 175^{\circ}C$ $T_c = 125^{\circ}C$		200	2000	A
1F	De l'orward current		-			4.0	Λ
V	Diada Farryard Valtaga	$I_F = 20A$ $T_i = 25^{\circ}C$ $T_j = 175^{\circ}C$	$T_{i} = 25^{\circ}C$		1.6	1.8	V
V _F Diode Forward Voltage	Diode Forward Voltage		$T_j = 175$ °C		2.0	2.4	V
Qc	Total Capacitive Charge	$I_F = 20A, V_R = 600V$ di/dt =800A/ μ s			56		nC
Q	T . 10	$f = 1MHz, V_R = 200V$	= 200V		130		E
	Total Capacitance	$f = 1 MHz, V_R =$	= 400V		100		pF
R_{thJC}	Junction to Case Thermal Resistance					1.5	°C/W

Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit	
V_{ISOL}	RMS Isolation Voltage, any terminal to case t = 1 min, 50/60Hz					V	
T_{J}	Operating junction temperature range			-40	150		
T_{JOP}	Recommended junction temperature under switching conditions			-40	T _J max -25	°C	
T_{STG}	Storage Temperature Range			-40	125		
$T_{\rm C}$	Operating Case Temperature			-40	100		
Torque	Mounting torque	To Heatsink	M5	2.5	4.7	N.m	
Wt	Package Weight				160	g	

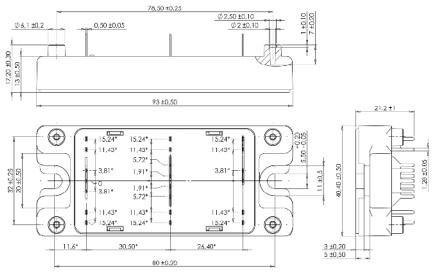
Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic	,	Min	Тур	Max	Unit
R ₂₅	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B _{25/85}	$T_{25} = 298.15 \text{ K}$			3952		K
ΔΒ/Β		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp \left[\frac{1}{R_{25/85}} \left(\frac{1}{T_{25}} - \frac{1}{T} \right) \right]}$$
 T: Thermistor temperature R_T: Thermistor value at T



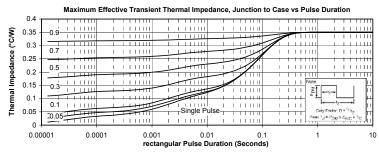
SP4 Package outline (dimensions in mm)

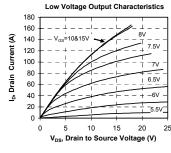


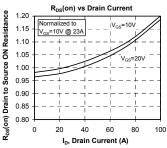
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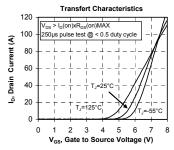
See application note APT0501 - Mounting Instructions for SP4 Power Modules on www.microsemi.com

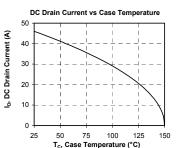
Typical MOSFET Performance Curve



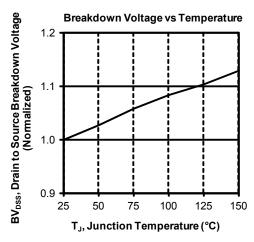


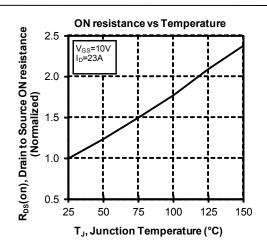


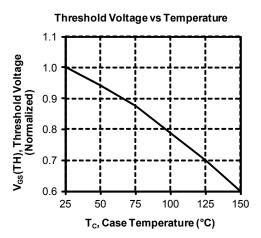


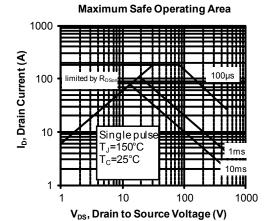


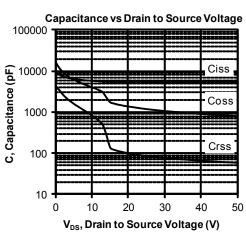


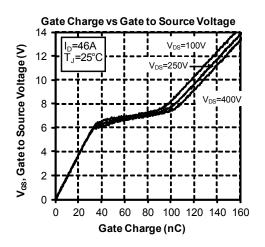




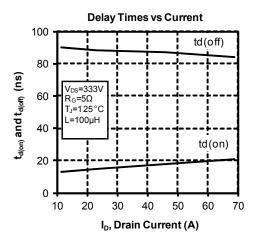


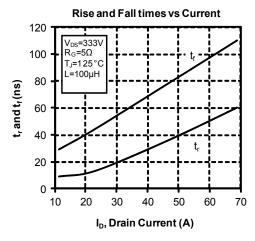


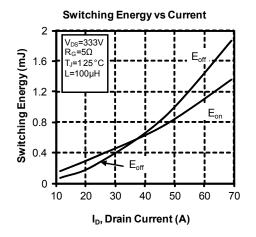


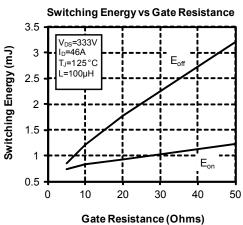


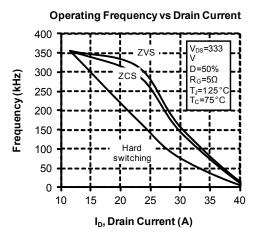


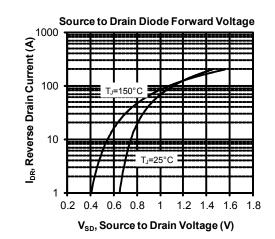






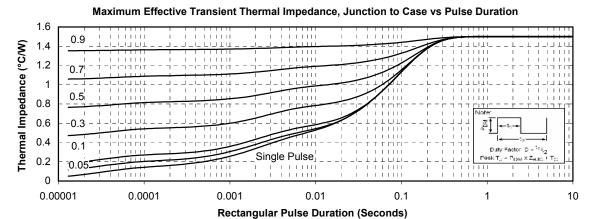


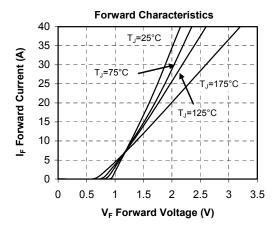


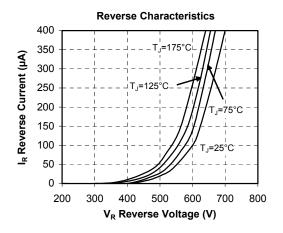


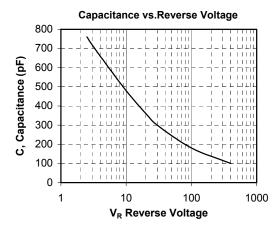


Typical SiC Diode Performance Curve









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